Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/072,404	STEEN, PAUL H.
Examiner	Art Unit
Len Tran	1725

	SEARCHED				
Class	Subclass	Date	Examiner		
164	463, 423	2/14/2006	LT		
	-				
			···i		
i					

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
164	all above	2/14/2006	LT	
interferen attached		2/14/2006	LT	

(INCLUDING SEARC	TOIRAIEG	'
	DATE	EXMR
		
		ļ